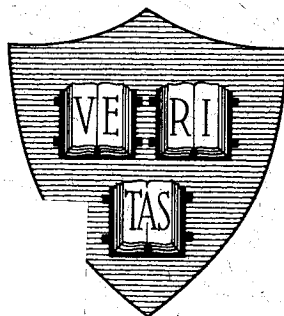


N.I.

Office of Naval Research
Contract N00014-67-A-0298-0005

NR-371-016
NATIONAL AERONAUTICS AND SPACE ADMINISTRATION
Grant NGR 22-007-056

A METHOD FOR PHOTOGRAPHING MICROWAVE WITH A POLAROID FILM



By

Seigo Iizuka

March 1968

Technical Report No. 558

Reproduction in whole or in part is permitted for
any purpose of the United States Government.

Division of Engineering and Applied Physics
Harvard University • Cambridge, Massachusetts

Facility Form 602

Accession Number	22035	(THRU)	
(PAGES)	26	(CODE)	1
(NASA CR OR TMX OR AD NUMBER)	CR-44305	(CATEGORY)	14

GPO PRICE \$
CFSTI PRICE(S) \$
Hard copy (HC) 3.00
Microfiche (MF) .65

653 July 65



Office of Naval Research
Contract N00014-67-A-0298-0005

NR - 371 - 016

National Aeronautics and Space Administration

Grant NGR-22-007-056

A METHOD FOR PHOTOGRAPHING MICROWAVE WITH A
POLAROID FILM

By

Keigo Iizuka

Technical Report No. 558

Reproduction in whole or in part is permitted for any purpose of the United States Government.

March 1968

The research reported in this document was made possible through support extended the Division of Engineering and Applied Physics, Harvard University by the U. S. Army Research Office, the U. S. Air Force Office of Scientific Research and the U. S. Office of Naval Research under the Joint Services Electronics Program by Contracts N00014-67-A-0298-0006, 0005, and 0008 and by the National Aeronautics and Space Administration under Grant NGR-22-007-056.

Division of Engineering and Applied Physics
Harvard University Cambridge, Massachusetts

A METHOD FOR PHOTOGRAPHING MICROWAVE WITH A
POLAROID FILM

By

Keigo Iizuka

Division of Engineering and Applied Physics
Harvard University Cambridge, Massachusetts

ABSTRACT

A regular Polaroid film has proved to be applicable to a quick and easy direct mapping of an electromagnetic field. The method utilizes the selective development of the film in accordance with the thermal image produced by the electromagnetic field. The power required for the creation of a clear image is about 0.06 watts per square inch. The time of exposure to the microwave is about 15 to 60 seconds.

The method would be most useful for preparing microwave holograms. It can also be applied to the mapping of the temperature distribution in space.

Introduction

When it is desired to measure an electromagnetic field over a large area, no simple technique is at present available other than mechanical scanning with a small probe. This has such disadvantages as discrete recording, disturbance of the original field by lead wires and supports, and a lack of economy of time. Microwave holography has suffered from this basic difficulty since no convenient analog to the photographic plate has existed at microwave frequencies.

It has been found that a regular Polaroid film can be used to map an electromagnetic field. The principle involved in the new method is the temperature dependence of the developing speed of a uniformly exposed film. The method has proved to be inexpensive and accurate. Actually, the intensity of a given field can be measured simply by holding the film by hand for less than one minute. No other equipment is required.

Principle and method

Figure 1 shows a cross-section of Polacolor Type 58 film which is normally used for taking instant 4" x 5" color pictures. The film packet consists of negative and positive layers and a developing agent. The film is first "sensitized" by briefly exposing it in a uniform manner to the light. The negative and positive with a pod containing the reagent are together pulled through the pair of rollers of a Polaroid 4 x 5 Land film holder Model 500. This action breaks the pod and releases the viscous processing reagent in a thin layer between the negative and positive. As soon as the reagent is in intimate contact with the film the development of the film starts. Immediately after the reagent has been spread, the film is placed directly into

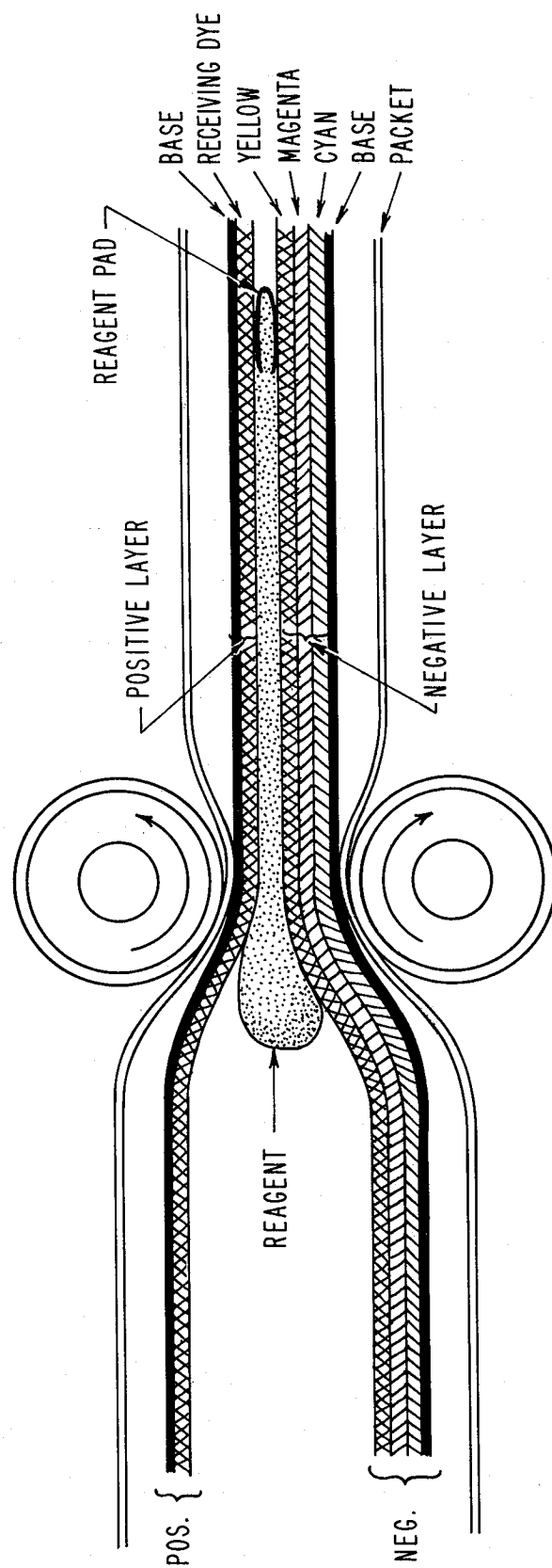


FIG. 1 CROSS-SECTION OF PACKET TYPE POLAROID COLOR FILM.

Introduction

When it is desired to measure an electromagnetic field over a large area, no simple technique is at present available other than mechanical scanning with a small probe. This has such disadvantages as discrete recording, disturbance of the original field by lead wires and supports, and a lack of economy of time. Microwave holography has suffered from this basic difficulty since no convenient analog to the photographic plate has existed at microwave frequencies.

It has been found that a regular Polaroid film can be used to map an electromagnetic field. The principle involved in the new method is the temperature dependence of the developing speed of a uniformly exposed film. The method has proved to be inexpensive and accurate. Actually, the intensity of a given field can be measured simply by holding the film by hand for less than one minute. No other equipment is required.

Principle and method

Figure 1 shows a cross-section of Polacolor Type 58 film which is normally used for taking instant 4" x 5" color pictures. The film packet consists of negative and positive layers and a developing agent. The film is first "sensitized" by briefly exposing it in a uniform manner to the light. The negative and positive with a pod containing the reagent are together pulled through the pair of rollers of a Polaroid 4 x 5 Land film holder Model 500. This action breaks the pod and releases the viscous processing reagent in a thin layer between the negative and positive. As soon as the reagent is in intimate contact with the film the development of the film starts. Immediately after the reagent has been spread, the film is placed directly into

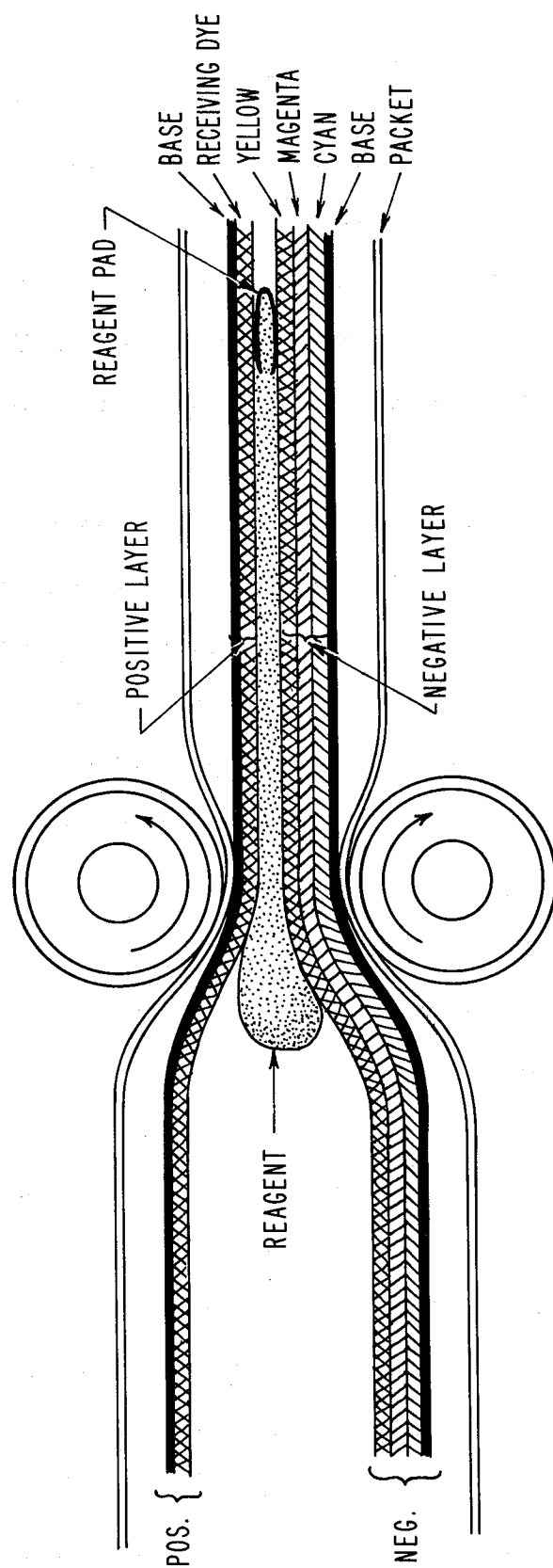


FIG. 1 CROSS-SECTION OF PACKET TYPE POLAROID COLOR FILM.

the electromagnetic field of a microwave. The formation of an "image" on the film by the field depends on the temperature sensitivity of the developing process of the film which has been uniformly exposed to the light.

The component of the electric field in the plane of the film generates heat in the exposed silver halide grains by means of an induced current. This raises the temperature of the grains in accordance with the square of the intensity of the field acting upon them. Thus, a thermal field which is a replica of the intensity distribution of the electromagnetic field is produced in the film. The localized heating in the grains leads to a localized increase in the diffusion rate of the developing reagent to the grain sites and additionally hastens the chemical development in the heated portions of the film.

The developer is removed from the film at a premature stage of the normal developing time. On the film a visible pattern corresponding to the field intensity distribution appears.

There are three ways to enhance the sensitivity of the film to the microwave.

(1) There is an optimum temperature at which the change in the growth of the silver grain with respect to the change in temperature is greatest. The experimental results indicate that this optimum temperature is in the vicinity of 25-35°F. The film is advantageously cooled to the temperature of dry ice before it is exposed to the microwave field because the film is warmed by the ambient temperature during the experiment. However, the reagent pod should not be cooled because it solidifies at around 32°F.

(2) The choice of the color of the light to which the film is pre-exposed for "sensitizing" the film also influences the sensitivity of the method. As shown in Fig. 1 the film has an emulsion-coated negative which contains dyes of different colors in nine separate layers at increasing distances from the surface of the negative. The time required for the developer for each of these dyes to reach the surface of the negative is dependent on the respective distance of each from this surface. If the negative is pre-exposed to light of a wavelength which allows only that dye which lies nearest the surface to reach this surface, a relatively short development time will result; if, on the other hand, the negative is pre-exposed to light of a wavelength which allows only that dye which lies farthest from the surface to reach this surface, then a relatively longer development time results. Thus, in the color film, pre-exposure to cyan colored light provides a longer developing time than is obtained by pre-exposure through a yellow filter. In effect, the effective thickness of the diffusing layer can be controlled by this technique. The choice of the color of the light is important. The pre-exposure to cyan colored light is useful for a relatively long exposure to a weak microwave field; the pre-exposure to yellow light is good for a short exposure to an intense microwave field.

In order to pre-expose the film, a box camera was utilized. The camera was aimed at a white sheet of paper which was illuminated by two carbon arc lights (5600°K) at 45° degree cycles. The incident illumination was measured by a Kodak Neutral Test Card. The reflected light from the card was 50 foot-candles. In order to obtain the desired cyan color, the film was first exposed through a blue filter (47) for $1/10$ second with a lens aperture of $F/9.5$ and then through a green filter (61) for $1/5$ second with the same lens aperture.

(3) The addition of a metal reflector placed parallel to the film was found to increase the sensitivity of the film at the cost of some disturbance of the original field. The maximum dissipation of microwave power in the film can be obtained by suitably adjusting the distance between the film and the metal reflector.

Besides Polacolor Type 58, other types of Polaroid film were tried. The black and white films like Types 52, 57, 55 P/N, and 107 were found applicable to the present purpose but with a reduced sensitivity to the imaging of the microwave field.

When only a small area of measurement is of interest, the 8-exposure pack (color $3\frac{1}{4} \times 4\frac{1}{4}$ - inch) was found quite handy except that it is difficult to cool only the portion of the film exclusive of the reagent pods because the latter are encased in the pack.

For the mapping of a large area of a microwave field, the Polaroid Radiographic Packets Type TLX for X-ray ($9\frac{3}{8} \times 10\frac{1}{2}$ - inch) were found most useful.

Fig. 2 shows the arrangement used for measuring a field intensity distribution at the open end of an L-band waveguide, ($f = 2,770$ MHz or $\lambda = 10.83$ cm), by means of a pre-cooled film packet.

Fig. 3 (a) was taken with Polacolor Type 58. The film was not exposed to the light before its exposure to the microwave field and the multi-color dyes present are responsible for the formation of the image. The exposure to the microwave field was for 15 seconds.

Fig. 3 (b) was taken with the same type of film and the same exposure time as Fig. 3 (a) except that only cyan colored dye was left in the film. Fig. 3 (c) was taken with a black and white film Type 52. The film was exposed to the microwave field for 2.5 seconds.

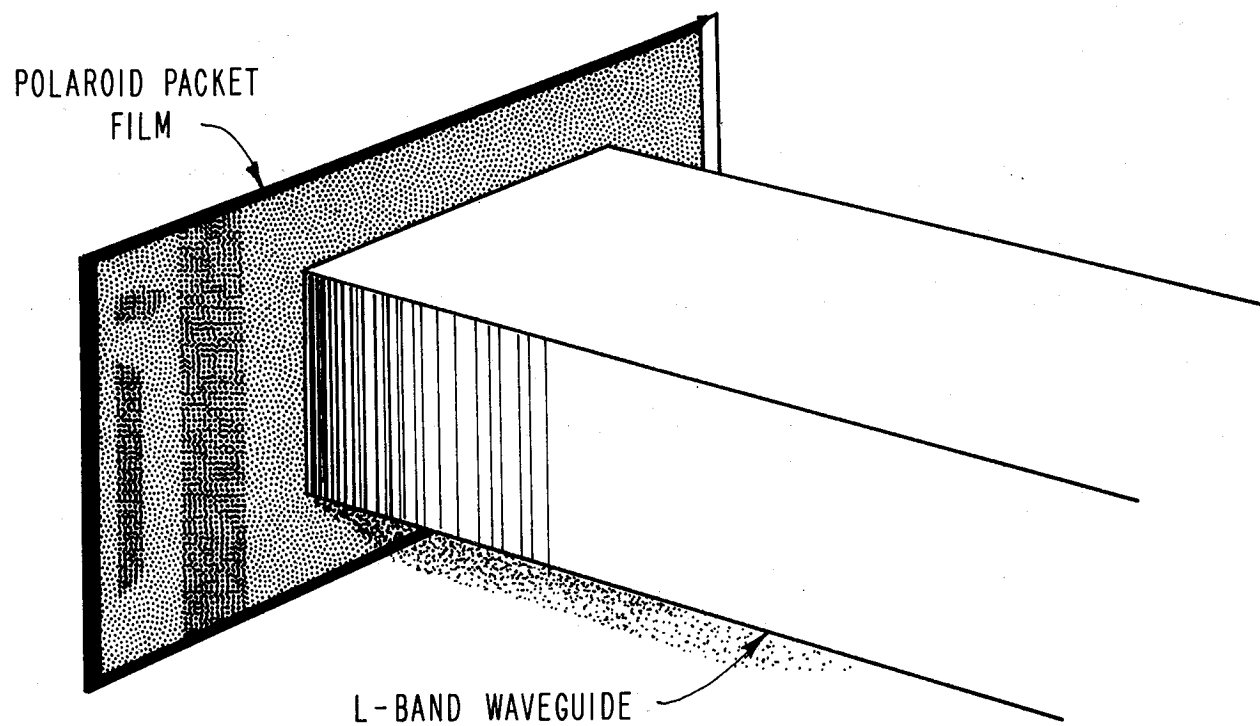
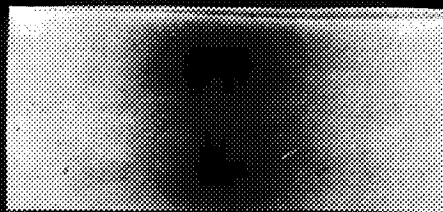
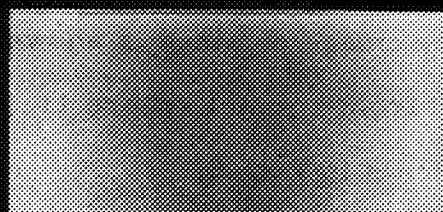


FIG. 2 MAPPING THE FIELD INTENSITY AT THE MOUTH OF AN OPEN WAVEGUIDE WITH A POLAROID FILM.



(a) WITH ALL COLOR DYES
(POLACOLOR 58)



(b) WITH CYAN DYE ONLY
(POLACOLOR 58)



(c) WITH BLACK AND WHITE
FILM (TYPE 52)

FIG. 3 FIELD INTENSITY OF AN OPEN-ENDED WAVEGUIDE MEASURED WITH A
USE OF POLAROID FILM.

Fig. 4 shows an arrangement for measuring Young's fringe pattern of a microwave signal ($f = 8,900$ MHz or $\lambda = 3.37$ cm) launched from two horns making an angle of 90 degrees between them. The packet film was placed at equal distances from the horns and at 45° degrees with respect to the incident waves. The image recorded is shown in Fig. 5. Polacolor Type 58 was used. The exposure time to the microwave field was 60 seconds.

Fig. 6 shows an arrangement for measuring the field scattered from a metal cylinder 17 mm in diameter. The E field was polarized in the direction of the axis of the cylinder. The film was oriented at 45 degrees with respect to the incident wave. The image obtained is shown in Fig. 7. A similar image of the field scattered from a metal sphere 11.1 mm in diameter in place of the cylinder is shown in Fig. 8.

Fig. 9 shows an arrangement for mapping the radiation pattern of an X-band horn. The reference field is superimposed so that the distribution of the phase front is also known. The film was held on one of the vertical edges of the horn parallel to the center line. The direction of the polarization of the E field was in the plane of the film.

Fig. 10 shows the image of a transmitting horn obtained by this method ($f = 8,900$ MHz). The location of the horn is to the right of the film and the reference signal impinges normally onto the plane of the film. The picture shows a wave front that grows toward the left; the wave fronts are parallel to one another.

Not only the field distribution but also the distribution of the charges along conductors can be mapped by the new method. Fig. 11 shows an arrangement for mapping the charge distribution along a monopole antenna over a ground plane.

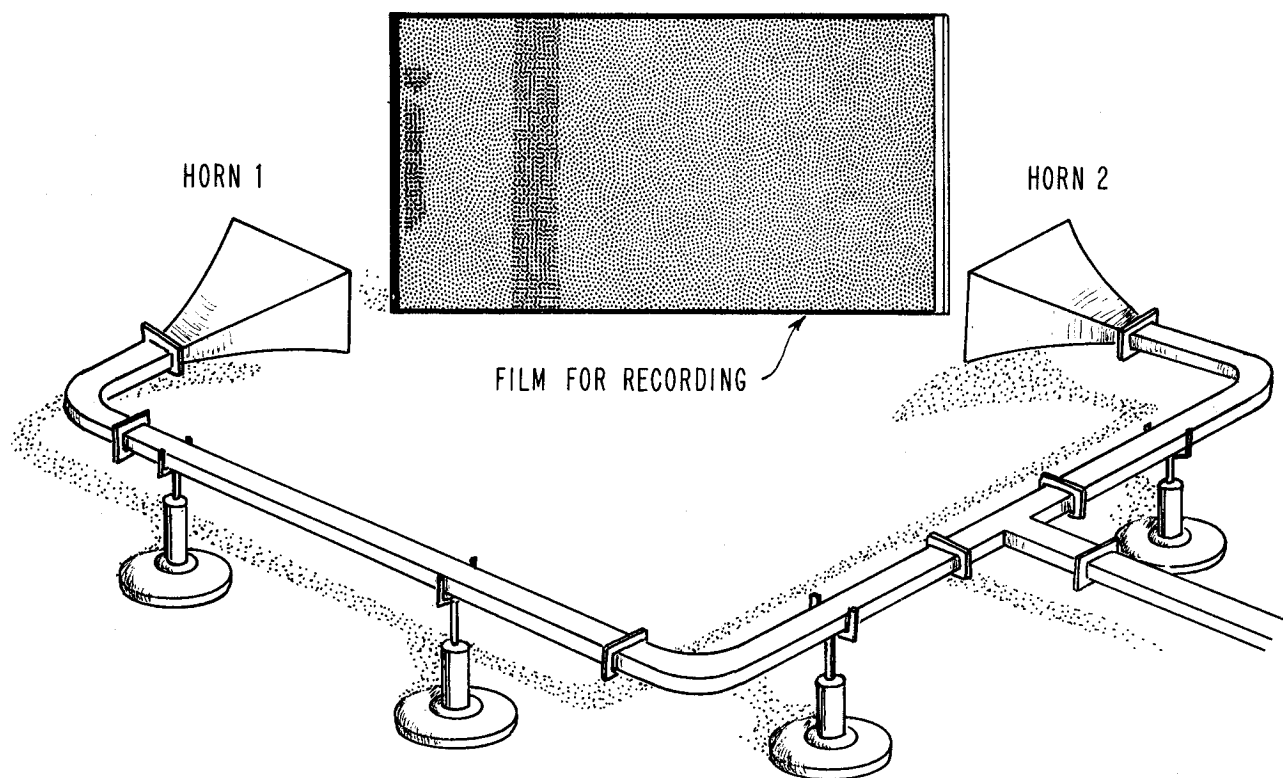


FIG. 4 ARRANGEMENT FOR MAPPING A YOUNG'S FRINGE PATTERN OF A MICROWAVE SIGNAL ($f = 8.900 \text{ MHz}$).



FIG. 5 IMAGE OF A YOUNG'S FRINGE
PATTERN FROM TWO X-BAND HORNS.

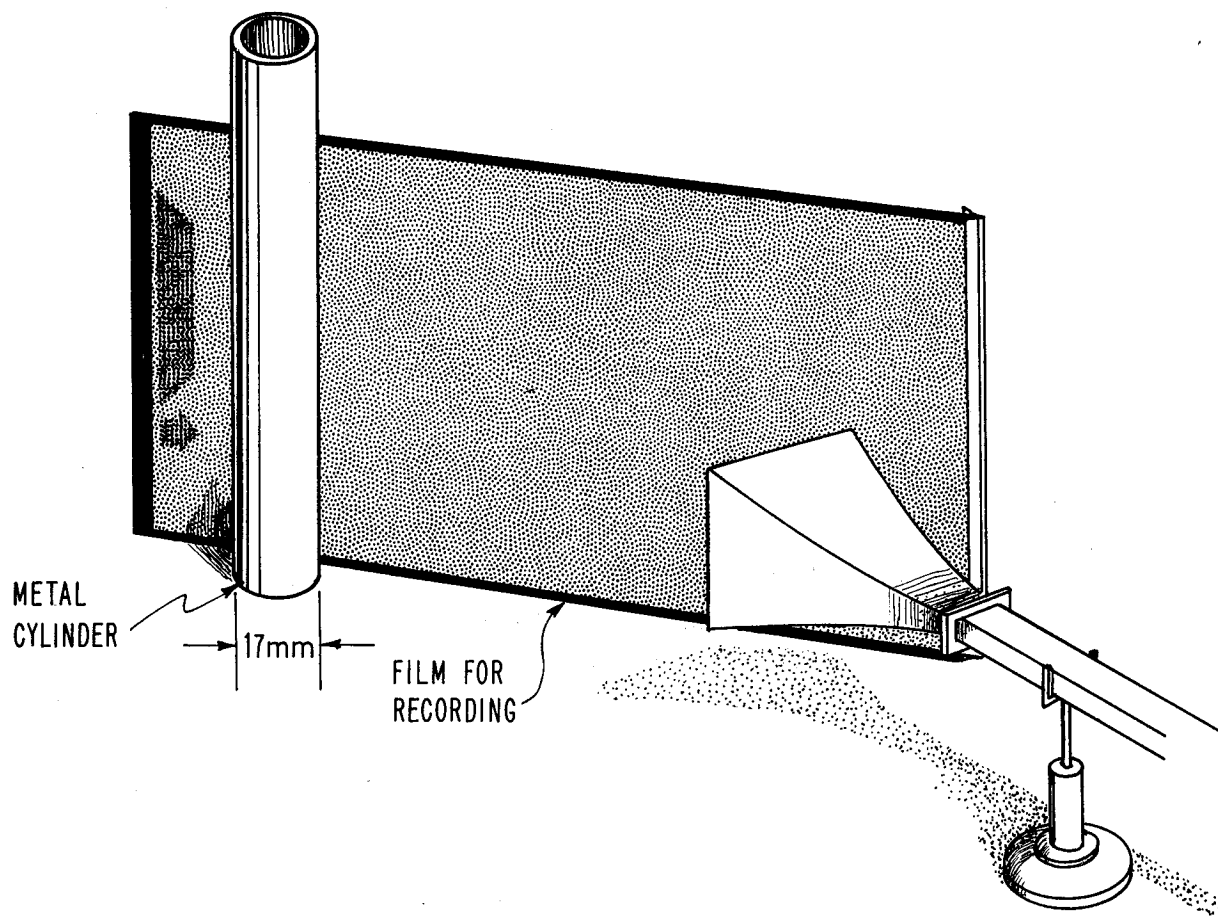


FIG. 6 ARRANGEMENT FOR MEASURING SCATTERED FIELD FROM A METAL CYLINDER .



FIG. 7 IMAGE OF THE SCATTERED FIELD
FROM A METAL CYLINDER 17 mm
IN DIAMETER.



FIG. 8 IMAGE OF THE SCATTERED FIELD
FROM A METAL SPHERE 11.1 mm
IN DIAMETER.

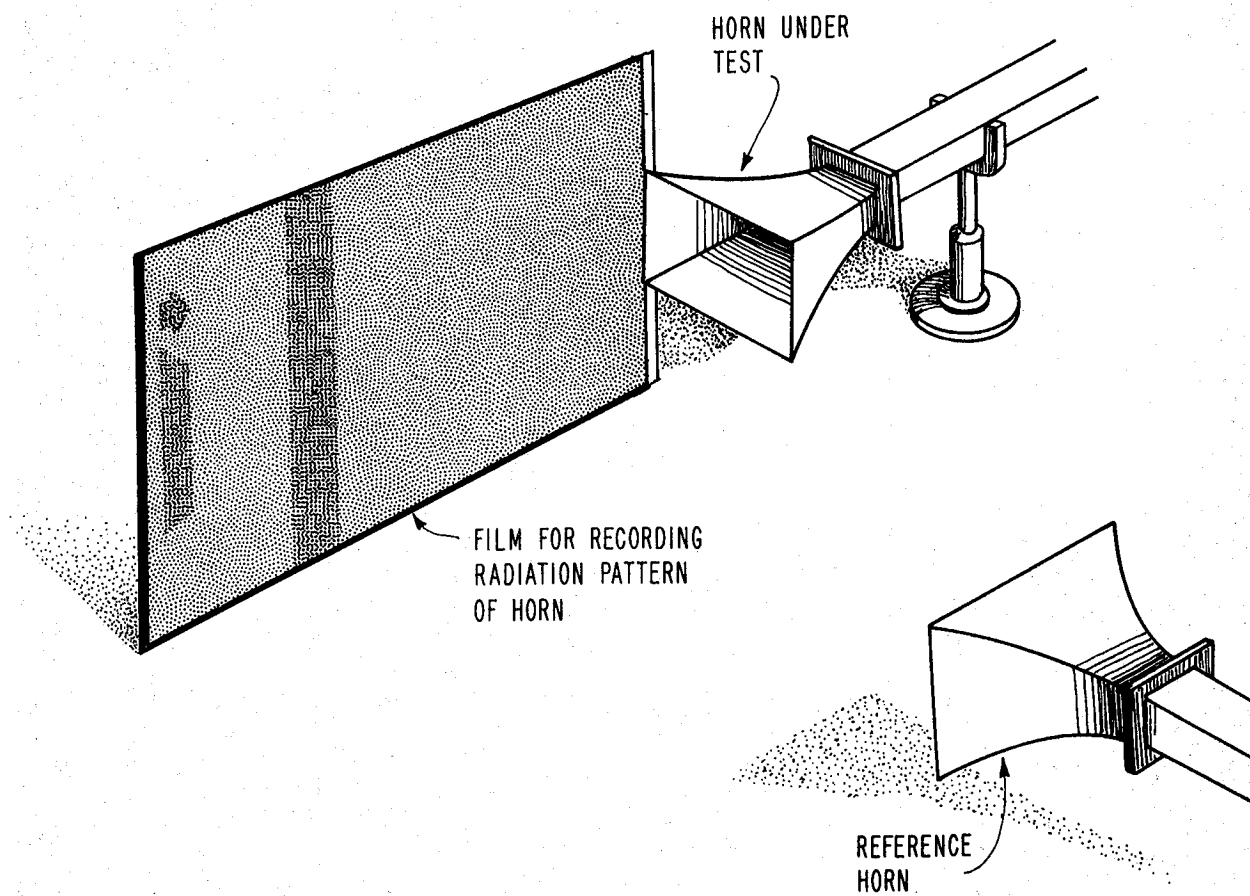


FIG. 9 ARRANGEMENT FOR MAPPING THE RADIATION PATTERN OF AN X-BAND HORN.

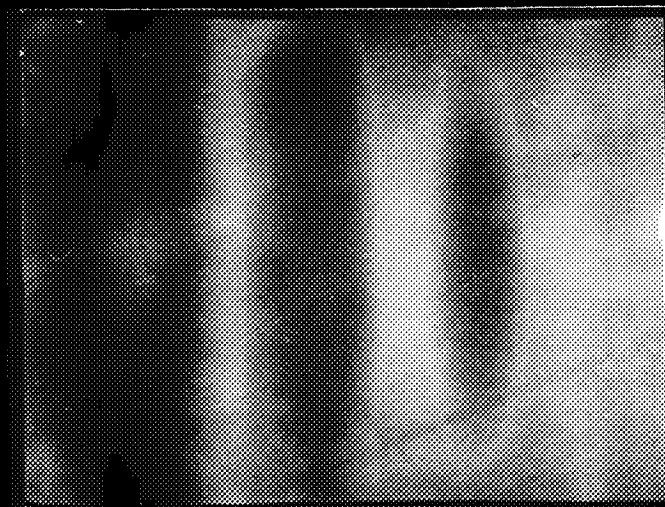


FIG.10 IMAGE OF AN X-BAND TRANSMITTING HORN.
THE LOCATION OF THE HORN IS TO THE RIGHT
OF THE FILM AND THE REFERENCE SIGNAL
IMPINGES NORMAL TO THE FILM SURFACE.

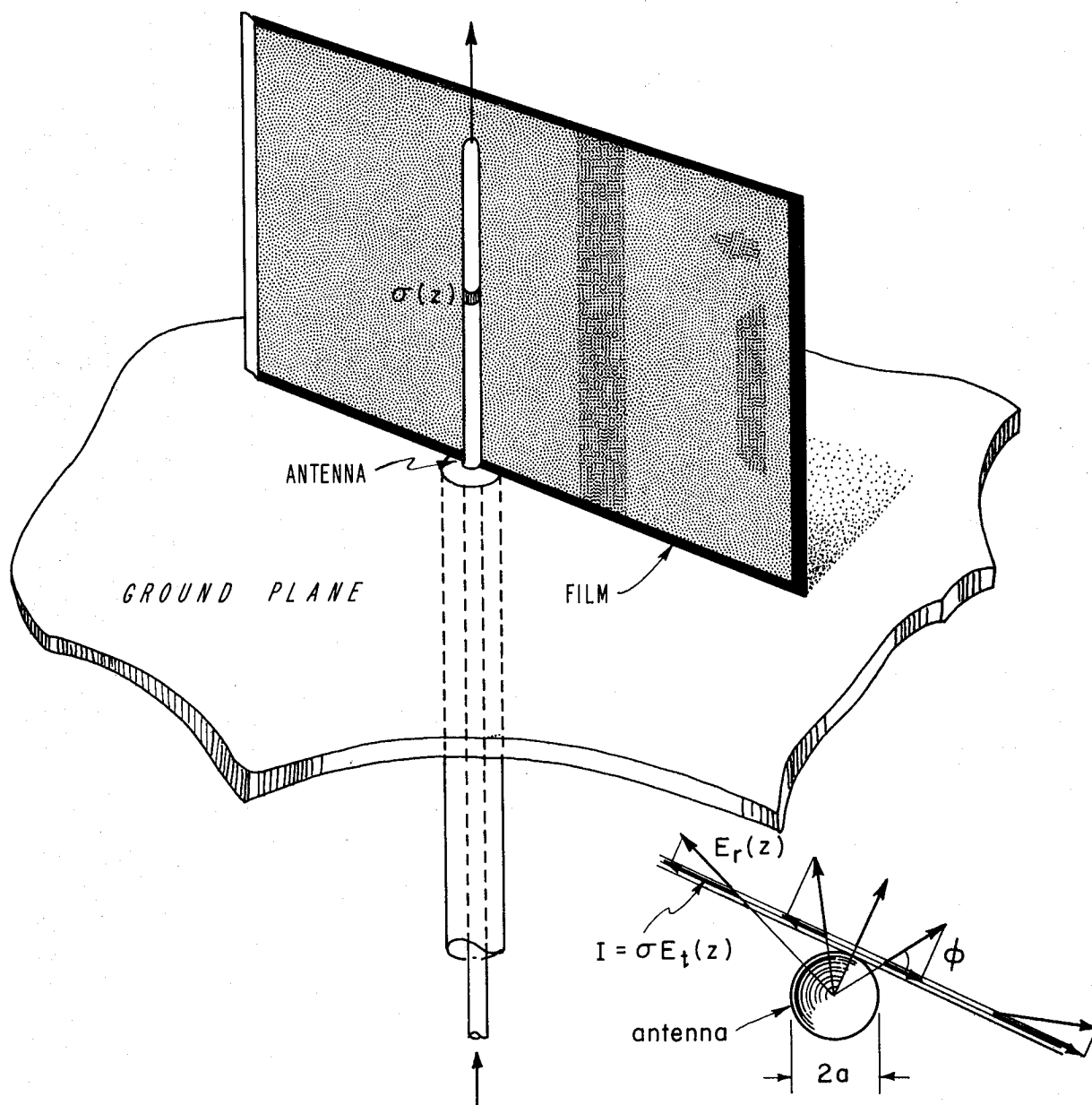


FIG. 11 ARRANGEMENT FOR MAPPING THE CHARGE DISTRIBUTION ALONG A MONOPOLE OVER A GROUND PLANE.

The film was placed in contact with the antenna and the ground plane. The radial component of the E field except near the tip of the antenna is

$$E_r(z) = \frac{a\sigma(z)}{r}$$

where $E_r(z)$ is the radial field intensity at z , $\sigma(z)$ is the surface charge density at z on the antenna, a is the radius of the antenna wire, r is the radial distance from the axis of the monopole.

The electric field responsible for inducing the current on the film is

$$E_t(z) = E_r(z) \cos \phi$$

where ϕ is the angle between the radial component of the electric field and the plane of the film. Thus, by knowing the mapping of $|E_t(z)|^2$ the distribution of $|\sigma(z)|$ can be obtained.

Fig. 12 shows the mapping of $|E_t(z)|^2$ along monopoles with $\beta h = \frac{2\pi}{\lambda} h = 4.64$ and $\beta h = 2.96$ at $f = 2,770$ MHz. The field near the driving-point could not be mapped because of the margin of the film. It is interesting to note that at the tip of the antenna a minimum surrounded by maxima in the immediate vicinity can be clearly seen. This may indicate a good power of resolution of the mapping. The minimum is that of the tangential component $E_t(h)$ of the field. The large component $E_r(h)$ is perpendicular to the surface of the film, $\phi = 90^\circ$. (See Fig. 11).

The minimum field intensity at frequencies between $1 \sim 10$ GHz which would suffice to produce a relatively clear image is approximately 0.06 watts per square inch. It would not be difficult to prepare a microwave

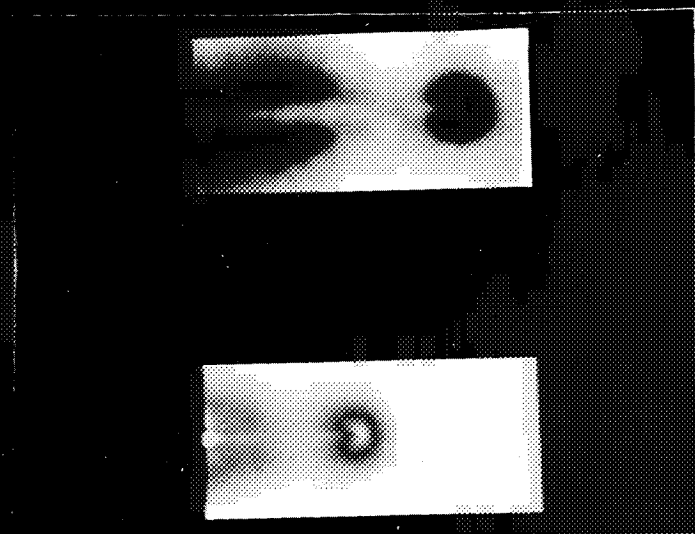


FIG. 12 MAPPING OF THE CHARGE DISTRIBUTION
ALONG THE MONOPOLE OVER A GROUND
PLANE $\beta h = 4.64$ ABOVE AND $\beta h = 2.96$

hologram with an area of 1,000 square wavelengths by this method utilizing only a common medium-sized X-or K-band magnetron.

So far a method has been described for mapping electromagnetic fields. However, the method is not limited to this application. It may be employed advantageously to record any physical phenomenon capable of generating a thermal image of the field to be recorded. For example, the temperature distribution within the flame of a candle was successfully mapped by holding the film vertically in the flame for a few seconds as shown in Fig. 13. The temperature distribution within the flame generates a corresponding distribution within the emulsion and causes the film to form an "image" whose intensity is directly proportional to the temperature distribution of the candle. The mapping of the temperature thus obtained is shown in Fig. 14. The bottom portion of the flame could not be mapped because it was in the margin of the film. The film was pre-exposed to magenta light of uniform intensity. The existence of a low temperature area at the lower center of the flame is also distinguishable in the mapping.

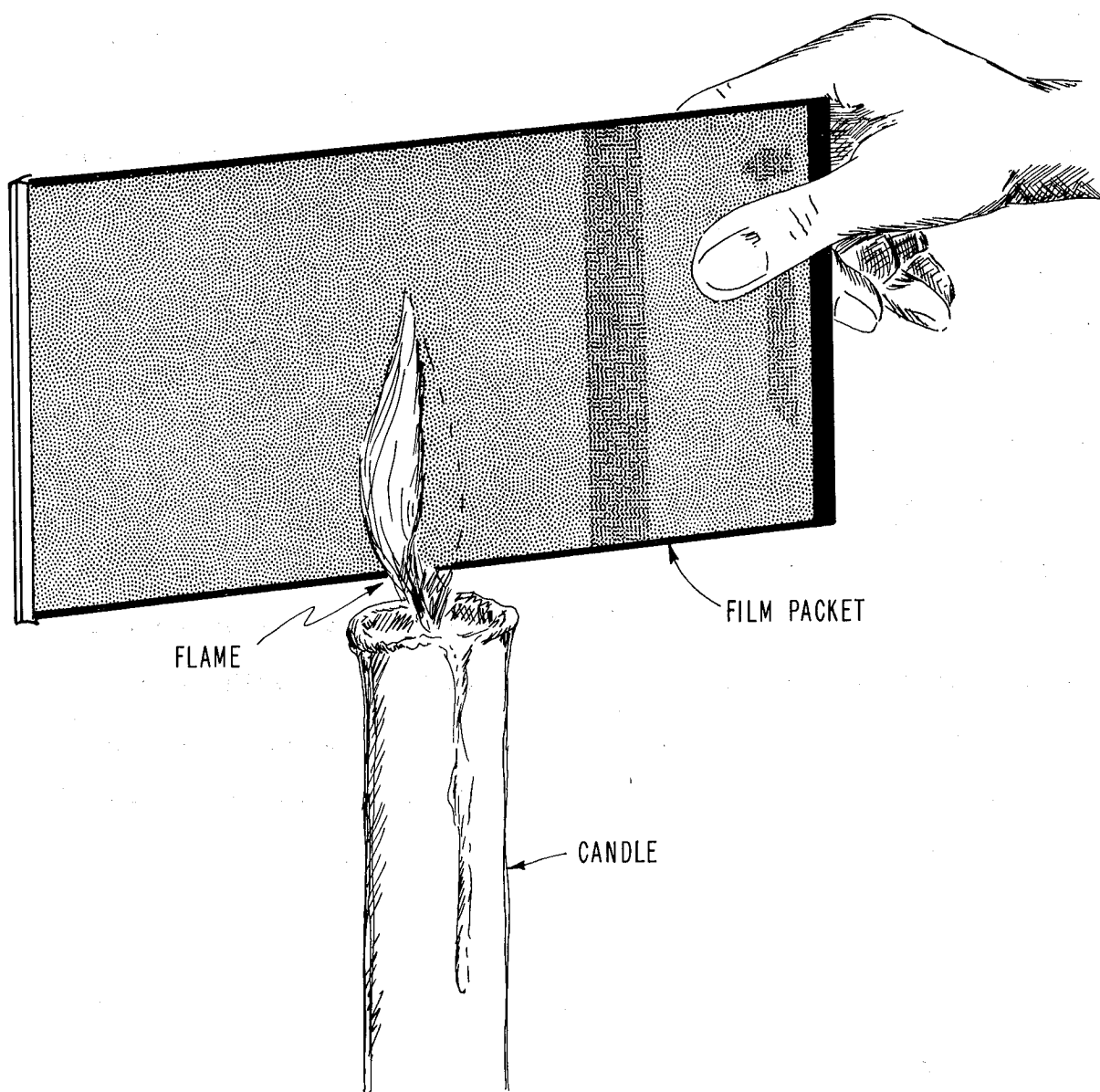


FIG. 13 QUICK WAY OF MAPPING THE CROSS-SECTIONAL TEMPERATURE DISTRIBUTION OF A CANDLE FLAME.



FIG.14 CROSS-SECTIONAL TEMPERATURE
DISTRIBUTION OF A CANDLE FLAME
MAPPED BY A POLAROID COLOR FILM

Acknowledgments

The author wishes to thank Professor R. W. P. King of Harvard University for correcting the manuscript. He is also indebted to Messrs. G. Trafford and M. Miller and Dr. R. Kodis of NASA Electronics Research Center of Cambridge, Massachusetts for their financial arrangements and to Messrs. P. Donaldson and A. Dionne for technical information.

List of Figures

- Fig. 1 Cross-section of Packet-type Polaroid Color film.
- Fig. 2 Mapping of the field intensity at the mouth of an open-ended waveguide with a Polaroid film.
- Fig. 3 Image of an open-ended waveguide measured with a use of Polaroid films
(a) with multi-color dyes (Polacolor 58)
(b) with only cyan dye (Polacolor 58)
(c) with black and white film (Type 52)
- Fig. 4 Arrangement for mapping Young's fringe pattern of a microwave signal ($f = 8,900$ MHz).
- Fig. 5 Image of Young's fringe pattern from two X-band horns.
- Fig. 6 Arrangement for measuring field scattered from a metal cylinder.
- Fig. 7 Image of the field scattered from a metal cylinder 17mm in diameter.
- Fig. 8 Image of the field scattered from a metal sphere 11.1mm in diameter.
- Fig. 9 Arrangement for mapping the radiation pattern of an X-band horn.
- Fig. 10 Image of an X-band transmitting horn. The location of the horn is to the right of the film and the reference wave impinges normal to the film surface.
- Fig. 11 Arrangement for mapping the charge distribution along a monopole over a ground plane.
- Fig. 12 Mapping of the charge distribution along monopoles over a ground plane. $\beta h = 4.64$ (above) and $\beta h = 2.96$.
- Fig. 13 Quick way to map the cross-sectional temperature distribution of a candle flame.
- Fig. 14 Cross-sectional temperature distribution of a candle flame mapped by a polaroid color film.

Joint Services Electronics Program
N00014-67-A-0298-0006, 0005, and 0008

Academy Library (DFSLB)
U. S. Air Force Academy
Colorado Springs, Colorado 80912

ADIC (ARO, INC)
Attn: Library/Documents
Arnold AFB, Tenn. 37389

Aeronautics Library
Graduate Aeronautical Laboratories
California Institute of Technology
1201 E. California Blvd.
Pasadena, California 91109

Aerospace Corporation
P. O. Box 9585
Los Angeles, Calif. 90045
Attn: Library Acquisitions Group

Airborne Instruments Laboratory
Dearpark, New York 11729

AFAL (AFV/R. D. Larson)
Wright-Patterson AFB
Ohio 45433

AFCL (CRMLR)
AFSC Research Library, Stop 29
L. C. Vansum Field
Bedford, Mass. 01731

AFETR (ETLIG-1)
STINPO Officer (for library)
Patrick AFB, Florida 32955

AFETR Technical Library
(ETV, MU-135)
Patrick AFB, Florida 32955

AFETC (FRBPP-2)
Technical Library
Edwards AFB, Calif. 93523

APGC (PHBPS-12)
Eglin AFB
Florida 32542

ARL (ART)
Wright-Patterson AFB
Ohio 45433

AULIT-9663
Maxwell AFB
Alabama 36112

Mr. Henry L. Bachman
Assistant Chief Engineer
Wheeler Laboratories
122 Cuttermill Road
Great Neck, N. Y. 11021

Bendix Pacific Division
11600 Sherman Way
North Hollywood, Calif. 91605

Colonel A. D. Blue
RTD (RTTL)
Bolling AFB
Washington, D. C. 20332

California Institute of Technology
Pasadena, California 91109
Attn: Documents Library

Carnegie Institute of Technology
Electrical Engineering Dept.
Pittsburg, Pa. 15213

Central Intelligence Agency
Attn: OCR/DD Publications
Washington, D. C. 20505

Chief of Naval Operations
OP-07
Washington, D. C. 20350 [2]

Chief of Naval Research
Department of the Navy
Washington, D. C. 20360
Attn: Code 427 [3]

Commandant
U. S. Army and General Staff College
Attn: Secretary
Fort Leavenworth, Kansas 66370

Commander
Naval Air Development and
Material Center
Johnsville, Pennsylvania 16974

Commanding General
Frankford Arsenal
Attn: SMUFA-L6000 (Dr. Sidney Ross)
Philadelphia, Pa. 19117

Commandant
U. S. Army Air Defense School
Attn: Missile Sciences Div. C and S Dept.
P. O. Box 939
Fort Bliss, Texas 79916

Commander
U. S. Naval Air Missile Test Center
Point Mugu, California 93041

Commanding General
Attn: STEWS-W5-VT
White Sands Missile Range
New Mexico 88002 [2]

Commanding General
U. S. Army Electronics Command
Fort Monmouth, N. J. 07703
Attn: AMSB-JC

RD-D
RD-G
RD-Q
RD-MAT
XL-D
XL-E
XL-C
XL-S
HL-D
HL-CT-R
HL-CT-P
HL-CT-L
HL-CT-O
HL-CT-I
HL-CT-A
NL-D
NL-A
NL-P
NL-R
NL-S
KL-E
KL-S
KL-T
VL-D
WL-D

Commanding General
U. S. Army Material Command
Attn: AMCRD-RS-DE-E
Washington, D. C. 20315

Commanding General
U. S. Army Missile Command
Attn: Technical Library
Redstone Arsenal, Alabama 35890

Commanding Officer
Naval Avionics Facility
Indianapolis, Indiana 46241

Commanding Officer
U. S. Army Limited War Laboratory
Attn: Technical Director
Aberdeen Proving Ground
Aberdeen, Maryland 21005

Commanding Officer
U. S. Army Materials Research Agency
Watertown Arsenal
Watertown, Massachusetts 02172

Commanding Officer
U. S. Army Security Agency
Arlington Hall
Arlington, Virginia 22212

Commanding Officer and Director
U. S. Naval Underwater Sound Lab.
Fort Triumphant
New London, Conn. 06460

Defense Documentation Center
Attn: TDIS
Cameron Station, Bldg. 5
Alexandria, Virginia 22314 [20]

Det No. 6, OAR (LOAR)
Air Force Unit Post Office
Los Angeles, Calif. 90045

Director
Advanced Research Projects Agency
Department of Defense
Washington, D. C. 20301

Director for Materials Sciences
Advanced Research Projects Agency
Department of Defense
Washington, D. C. 20301

Director
Columbia Radiation Laboratory
Columbia University
558 West 140th Street
New York, New York 10027

Director
Coordinated Science Laboratory
University of Illinois
Urbana, Illinois 61801

Director
Electronic Research Laboratory
University of California
Berkeley, California 94720

Director
Electronic Sciences Laboratory
University of Southern California
Los Angeles, California 90007

Director
Microwave Laboratory
Stanford University
Stanford, California 94305

Director - Inst. for Exploratory
Research
U. S. Army Electronics Command
Attn: Mr. Robert O. Parker
Executive Secretary, JSTAC
(AMSEL-XL-D)
Fort Monmouth, N. J. 07703

Director
National Security Agency
Fort George G. Meade
Maryland 20755
Attn: James T. Tippett

Director, Naval Research Laboratory
Technical Information Officer
Washington, D. C.
Attn: Code 2000 [8]

Director
Research Laboratory of Electronics
Massachusetts Institute of Technology
Cambridge, Mass. 02139

Director
Stanford Electronics Laboratories
Stanford University
Stanford, California 94305

Commanding Officer
Naval Ordnance Laboratory
Corona, California 91720

Commanding Officer
Naval Ordnance Laboratory
White Oak, Maryland 21502 [2]

Commanding Officer
Naval Ordnance Test Station
China Lake, Calif. 93555

Commanding Officer
Naval Training Device Center
Orlando, Florida 32811

Commanding Officer
Office of Naval Research Branch Office
1010 East Green Street
Pasadena, California

Commanding Officer
Office of Naval Research Branch Office
219 South Dearborn Street
Chicago, Illinois 60604

Commanding Officer
Office of Naval Research Branch Office
455 Summer Street
Boston, Massachusetts 02210

Commanding Officer
Office of Naval Research Branch Office
207 West 24th Street
New York, New York 10011

Commanding Officer
Office of Naval Research Branch Office
Box 19, Fleet Post Office
New York 095-1 [1]

Commanding Officer
U. S. Army Electronics R & D Activity
White Sands Missile Range
New Mexico 88002

Commanding Officer
U. S. Army Engineer R & D Laboratory
Attn: TDRPO Branch
Fort Belvoir, Virginia 22060

Commanding Officer
U. S. Army Research Office (Durham)
Attn: CRD-AA-IP (Richard D. Utah)
Box CM, Duke Station
Durham, North Carolina 27706

Commanding General
USASTRATCOM
Technical Information Center
Fort Huachuca, Arizona 85613

Commanding Officer
Harry Diamond
Attn: Dr. Berthold Altman (AMXDO-TI)
Connecticut Ave. & Van Ness St. NW
Washington, D. C. 20043

Commanding Officer
Human Engineering Laboratories
Aberdeen Proving Ground
Maryland 21005

Commanding Officer
U. S. Army Ballistics Research Lab.
Attn: V. W. Richards
Aberdeen Proving Ground
Maryland 21005

Director, USAF Project RAND
Attn: Library
Air Force Liaison Office
The RAND Corporation
1700 Main Street
Santa Monica, Calif. 90406
Attn: Library

Director
U. S. Army Engineer Center,
Intelligence and Mapping
Research and Development Agency
Fort Belvoir, Virginia 22060

Director
U. S. Naval Observatory
Washington, D. C. 20350

Director, U. S. Naval Security Group
Attn: G43
3501 Nebraska Avenue
Washington, D. C. 20390

Division of Engineering and Applied
Physics
150 Science Hall
Harvard University
Cambridge, Massachusetts 02138

Professor A. A. Dougal, Director
Laboratories for Electronics and
Related Sciences Research
University of Texas
Austin, Texas 78712

ESD (ESTH)
L. G. Hanscom Field
Bedford, Mass. 01731 [2]

European Office of Aerospace Research
Shell Building
47 Rue Carlesteven
Brussels, Belgium [2]

Colonel Robert E. Fontana
Dept. of Electrical Engineering
Air Force Institute of Technology
Wright-Patterson AFB, Ohio 45433

General Electric Company
Research Laboratories
Schenectady, New York 12301

Professor Nicholas George
California Institute of Technology
Pasadena, California 91109

Coddard Space Flight Center
National Aeronautics and Space Admin.
Attn: Library, Documents Section
Code 250
Green Belt, Maryland 20771

Dr. John C. Hancock, Director
Electronic Systems Research Laboratory
Purdue University
Lafayette, Indiana 47907

Dr. H. Harrison, Code RRE
Chief, Electrophysics Branch
National Aeronautics and Space Admin.
Washington, D. C. 20546

Head, Technical Division
U. S. Naval Counter Intelligence
Support Center
Fairmont Building
4420 North Fairfax Drive
Arlington, Virginia 22203

Headquarters
Defense Communications Agency
The Pentagon
Washington, D. C. 20305

Dr. L. M. Hollinsworth
AFRL (CRU)
L. G. Hanscom Field
Bedford, Massachusetts 01731

Hunt Library
Carnegie Institute of Technology
Schenectady Park
Pittsburgh, Pa. 15213

The Johns Hopkins University
Applied Physics Laboratory
8141 Georgia Avenue
Silver Spring, Maryland 20910
Attn: Boris W. Konrad
Document Librarian

Lt. Col. Robert B. Kolisch
Chief, Electronics Division
Directorate of Engineering Sciences
Air Force Office of Scientific Research
Arlington, Virginia 22209 [5]

Colonel Kee
AFBETC
Hq. USAF
Room 1D-433, The Pentagon
Washington, D. C. 20330

Dr. S. Beneset Levin, Director
Institute for Exploratory Research
U. S. Army Electronics Command
Fort Monmouth, New Jersey 07703

Los Alamos Scientific Laboratory
Attn: Reports Library
P. O. Box 1663
Los Alamos, New Mexico 87544

Librarian
U. S. Naval Electronics Laboratory
San Diego, California 92162 [2]

Lockheed Aircraft Corp.
P. O. Box 568
Sunnyvale, California 94088

Dr. I. B. Mirmam
AFSC (SC7)
Andrews Air Force Base, Maryland

Lt. Col. Bernard S. Morgan
Frank J. Sellar Research Laboratory
U. S. Air Force Academy
Colorado Springs, Colorado 80912

Dr. G. J. Murphy
The Technological Institute
Northwestern University
Evanston, Illinois 60201

Mr. Peter Murray
Air Force Avionics Laboratory
Wright-Patterson AFB, Ohio 45433

NASA Lewis Research Center
Attn: Library
21000 Brookpark Road
Cleveland, Ohio 44135

NASA Scientific & Technical
Information Facility
Attn: Acquisitions Branch (S/AR/DL)
P. O. Box 31
Arlington, Virginia 22204 [2]

National Science Foundation
Attn: Dr. John H. Lehman
Division of Engineering
1600 G Street, NW
Washington, D. C. 20550

National Security Agency
Attn: SS - James Tippet
Office of Research
Fort George G. Meade, Maryland 20755

Naval Air Systems Command
AFAL Air Test Center
Washington, D. C. 20360 [2]

Naval Electronics Systems Command
ELFX 03
Falls Church, Virginia 22046 [2]

Naval Ordnance Systems Command
ORD 32
Washington, D. C. 20360 [2]

Naval Ordnance Systems Command
SHF 035
Washington, D. C. 20360

Naval Ship Systems Command
SHIP 031
Washington, D. C. 20360

New York University
College of Engineering
New York, New York 10019

Dr. H. V. Noble
Air Force Avionics Laboratory
Wright-Patterson AFB, Ohio 45433

Office of Deputy Director
(Research and Information Rm. 3D1031)
Department of Defense
The Pentagon
Washington, D. C. 20301

Polytechnic Institute of Brooklyn
55 Johnson Street
Brooklyn, New York 11201
Attn: Mr. Jerome Fox
Research Coordination

RAD (EMAL-1)
Griffis AFB, New York 13442
Attn: Documents Library

Raytheon Company
Bedford, Mass. 01710
Attn: Librarian

Lt. Col. J. L. Reeves
AFSC (SC3B)
Andrews Air Force Base, Md. 20331

Dr. A. A. Dougal
Asst. Director of Research
Office of Defense Res. and Eng.
Department of Defense
Washington, D. C. 20301

Research Plans Office
U. S. Army Research Office
1045 Columbia Pike
Arlington, Virginia 22204

Dr. H. Robt, Deputy Chief Scientist
U. S. Army Research Office (Durham)
Durham, North Carolina 27705

Emil Schafer, Head
Electronics Properties Info. Center
Hughes Aircraft Company
Culver City, California 90230

School of Engineering Sciences
Arizona State University
Tempe, Arizona 85281

SAMSO (SMSDI-STINFO)
AF Unit Post Office
Los Angeles, California 90045

SSD (SSTR/La. Starbuck)
AFUSO
Los Angeles, California 90045

Superintendent
U. S. Army Military Academy
West Point, New York 10996

Colonel A. Swan
Aerospace Medical Division
AMD (AMRXII)
Brooks AFB, Texas 78235

Syracuse University
Dept. of Electrical Engineering
Syracuse, New York 13210

University of California
Santa Barbara, California 93106
Attn: Library

University of Calif. at Los Angeles
Dept. of Engineering
Los Angeles, California 90024

University of Michigan
Electrical Engineering Dept.
Ann Arbor, Michigan 48106

U. S. Army Munitions Command
Attn: Technical Information Branch
Piscataway Arsenal
Dover, New Jersey 07801

U. S. Army Research Office
Attn: Physical Sciences Division
1545 Columbia Pike
Arlington, Virginia 22204

U. S. Atomic Energy Commission
Division of Technical Information Ext.
P. O. Box 64
Oak Ridge, Tenn. 37831

Dept. of Electrical Engineering
Texas Technological College
Lubbock, Texas 79409

U. S. Naval Weapons Laboratory
Dahlgren, Virginia 22448

Major Charles Wiespy
Technical Division
Deputy for Technology
Space Systems Division, AFSC
Los Angeles, California 90045

The Walter Reed Institute of Research
Walter Reed Medical Center
Washington, D. C. 20012

AFSC (SCTR)
Andrews Air Force Base
Maryland 20331

Weapons Systems Test Division
Naval Air Test Center
Patuxent River, Maryland 20670
Attn: Library

Weapons Systems Evaluation Group
Attn: Col. Daniel W. McElwee
Department of Defense
Washington, D. C. 20305

Yale University
Engineering Department
New Haven, Connecticut 06720

Mr. Charles F. Yost
Special Asst. to the Director of Research
NASA
Washington, D. C. 20546

Dr. Leo Young
Stanford Research Institute
Menlo Park, California 94025

Unclassified

Security Classification

DOCUMENT CONTROL DATA - R & D

Security classification of title, body of abstract and indexing annotation must be entered when the overall report is classified

1. ORIGINATING ACTIVITY (Corporate author)

Division of Engineering and Applied Physics
Harvard University
Cambridge, Massachusetts 02138

2a. REPORT SECURITY CLASSIFICATION

Unclassified

2b. GROUP

3. REPORT TITLE

A METHOD FOR PHOTOGRAPHING MICROWAVE WITH A POLAROID
FILM

4. DESCRIPTIVE NOTES (Type of report and, inclusive dates)

Interim technical report

5. AUTHOR(S) (First name, middle initial, last name)

Keigo Iizuka

6. REPORT DATE

March 1968

7a. TOTAL NO. OF PAGES

26

7b. NO. OF REFS

0

8a. CONTRACT OR GRANT NO.

NASA Grant NGR 22-007-056

b. PROJECT NO.

N00014-67-A-0298-0005

c.

d.

9a. ORIGINATOR'S REPORT NUMBER(S)

Technical Report No. 558

9b. OTHER REPORT NO(S) (Any other numbers that may be assigned this report)

10. DISTRIBUTION STATEMENT

Reproduction in whole or in part is permitted for any purpose of the
United States Government.

11. SUPPLEMENTARY NOTES

12. SPONSORING MILITARY ACTIVITY

Office of Naval Research

13. ABSTRACT

A regular Polaroid film has proved to be applicable to a quick and easy direct mapping of an electromagnetic field. The method utilizes the selective development of the film in accordance with the thermal image produced by the electromagnetic field. The power required for the creation of a clear image is about 0.06 watts per square inch. The time of exposure to the microwave is about 15 to 60 seconds.

The method would be most useful for preparing microwave holograms. It can also be applied to the mapping of the temperature distribution in space.

14. KEY WORDS	LINK A		LINK B		LINK C	
	ROLE	WT	ROLE	WT	ROLE	WT
Method for mapping field or charge distribution Temperature sensitivity of developing process Thermal image of a temperature distribution						